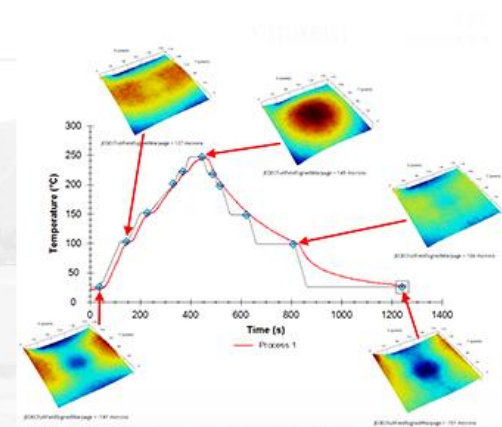
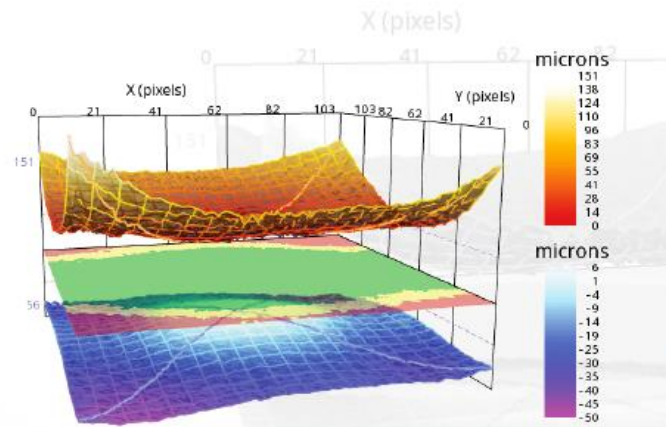


Thermal Warpage Metrology

Akrometrix's systems allow for a full field of view, single shot warpage measurement over a temperature profile (-25°C to 300°C) on a variety of substrates up to 600mm x 600mm.

Useful for QA, Process Control and R&D, our systems are the industry standard for sub-micron warpage and strain metrology.



THERMAL WARPAGE | CTE & STRAIN | INTERFACE ANALYSIS

